



# **Empowering Innovation**

## MunEDA @ DAC Design Automation Conference - Austin 2017



## Dear MunEDA Friends & Users,

We are pleased to invite you to visit our MunEDA booth and workshops at 54rd DAC Exhibition, Mon-Wed June 19-21 2017 Austin, TX (www.dac.com).

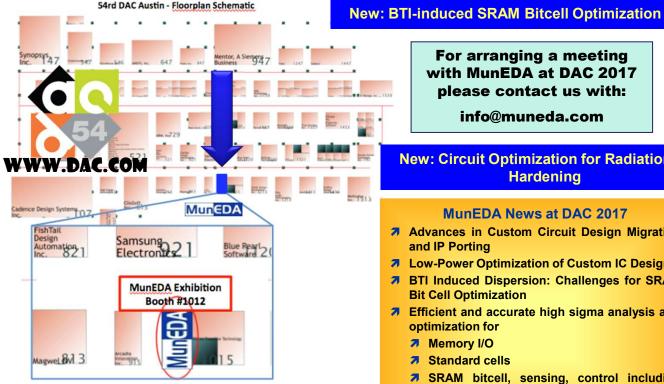
### MunEDA booth # 1012 in main exhibition hall



Circuit Schematic Migration & IP **Porting** 

Variation Analysis, PVT, Monte Carlo & High-Sigma

Circuit Sizing for Low Power, Yield & Reliability



## MunEDA DAC Special Topic: **Low Power Circuit Sizing for IoT**

- Why is multi-objective automated circuit sizing challenging for IoT designs.
- > How can MunEDA automated sizing tools be leveraged to achieve high-performance and reliable to IoT designs.
- How are statistices incorporated into sizing to consider device mismatch and process centering.
- What is the technology behind the MunEDA automated sizing environment - with enouth math/statistics to be interesting but not overwhelming.
- How can MunEDA sensitivity-based tools be useful to test and confirm and validate current intuition of my IoT designs

Ask for our special introduction Low Power Circuit Sizing for IoT, info@muneda.com

For arranging a meeting with MunEDA at DAC 2017 please contact us with:

info@muneda.com

**New: Circuit Optimization for Radiation** Hardening

#### MunEDA News at DAC 2017

- Advances in Custom Circuit Design Migration and IP Porting
- **Low-Power Optimization of Custom IC Designs**
- BTI Induced Dispersion: Challenges for SRAM **Bit Cell Optimization**
- Efficient and accurate high sigma analysis and optimization for
  - Memory I/O
  - Standard cells
  - SRAM bitcell, sensing, control including hierarchical large circuit analysis
- PCM targeting for debugging yield issues
- Full Custom Design for Reliability, Aging & **Radiation Hardening**

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See you all in Austin for 2017 MunEDA DAC Exhibition and Workshops – www.muneda.com